

24 channel Analogue IC Tester Module

V-I test capability

Number of test channels:	24 + 2 probes and references
Test voltage:	2 V to 50 V peak to peak
Voltage resolution:	8 to 12 bits
Test frequency:	37.5 Hz to 12 kHz
Test current:	1 μ A to 150 mA
Source impedance:	100 Ohm to 1 M
Test waveforms:	Sine, square, triangle, ramp, pulse
Waveform modes:	V-I, V-T, I-T
Waveform display:	Multi-plot with single waveform zoom
Waveform comparison:	Automatic comparison algorithm for good and bad boards using live probes or disk
V-I comparison tolerance:	50 mV to 500 mV with 50 mV resolution
Package support:	DIL, SOIC, PLCC, QFP and variants with MultiProbes
Pulse output:	Positive, negative or bipolar for thyristors/triacs
Pulse amplitude:	Adjustable to +/-10 V
Calibration:	Can be calibrated by user

Analogue functional test capability

Number of I/O channels:	24 independent + 3 special discrete channels
Driver voltage:	-12 V to +12 V
Driver voltage resolution:	10 bit
Driver output current:	200 mA max sink or source
Driver states:	Voltage source, current source, off
Discrete source current:	10 μ A - 150 mA. (driving a load returned to 0 V)
Driver source impedance:	34 Ohm (34 Ohm, 1 k or 10 k on discrete channels)
Sensor input voltage:	+/- 24 V
Sensor voltage protection:	+/- 50 V
Sensor input impedance:	2 M
Sensor voltage resolution:	12 bit
Restrict voltage:	-10 V to +10 V
Restrict voltage resolution:	8 bit
Sensor current measurement:	1 mA to 150 mA (10 nA to 150 mA on discrete channels)
Sensor current resolution:	12 bit
Sensor current input impedance:	50 Ohm (50 Ohm, 1 k, 10 k or 1 M on discrete channels)
Short detection threshold:	<4 Ohm
Link detection threshold:	<10 Ohm
Test modes:	Single, unconditional loop, pass loop, fail loop
Test clip positioning:	Automatically adjusts for clip orientation
Circuit compensation:	Automatically modifies test for IC/PCB connections
Test trace:	Test waveforms and voltages displayed
Test analysis:	Displays test parameters such as gain, hfe, feedback
IC test capability:	Op-amps, comparators, DACs, ADCs, switches and special function analogue ICs in-circuit.
Discrete test capability:	Transistors, FETs, thyristors, triacs in- or out-of-circuit
IC test libraries:	Analogue, discrete, package, user
Result comparison:	Results can be saved for good/bad board comparison
Package support:	DIL, SOIC, PLCC and variants with MultiProbe kits
SLIM test programming:	Structured programming language for library additions

Other specifications

Electrical input:	(typical) +12 V, 1 A(max) (typical) -5 V, 750 mA (typical) -12 V, 100 mA
Dimensions:	147 x 202 x 42 mm
Weight:	1 kg

Accessories

Standard	1 x SMD test tweezer set and adapters 1 x 24 way test clip and cable assembly 1 x Blue V-I probes and adapter 1 x Yellow V-I probes and adapter 2 x Pulse leads 2 x Ground leads 3 x Discrete leads
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Options

Internal fitting	PCI interface
External fitting	MultiLink case (cost option) with serial or parallel connection External case (cost option) which can hold up to 4 SYSTEM 8 modules.

The ABI development team strive continually to improve their products for the benefit of the customer. The specification of current products may therefore vary from that described in this brochure.



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64 channel Board Fault Locator Module

Digital IC test capability

Number of I/O channels:	64-256
Number of guard outputs:	4 or 8
Live comparison:	64 x 2, 128 x 2 with additional modules
Drive output voltage:	TTL/CMOS compatible
Drive output current:	Device dependent Typical H-L 80mA @ 0.6V Typical L-H 200mA @ 2V Max. 400mA
Drive slew rate:	>100V/ μ s
Receive input:	+/-10V
Input impedance:	10k
Termination:	Programmable for tri-state/open collector
Drive states:	Low, high, tri-state
Over voltage protection:	<0.5V, >5.5V
Test time:	Dependent on device
Circuit modes:	In-circuit. Out-of-circuit (with adapter)

Power supply for board under test

Automatic power supply:	1 x 5V @ 5A fixed (2 x 5V @ 5A fixed for 128 channels)
Over voltage protection:	7V
Short circuit current:	7A

Test modes

Single:	Single test
Loop:	Unconditional, loop while good, loop while bad
Auto:	Find tightest valid thresholds

Test thresholds

Resolution:	100mV
Low levels:	TTL 0.1V to 1.1V CMOS 0.1V to 1.5V
Switching levels:	TTL 1.0V to 2.3V CMOS 1.0V to 3.0V
High levels:	TTL 1.9V to 4.9V CMOS 1.9V to 4.9V
Swept low levels:	TTL 0.1V to 1.1V CMOS 0.1V to 1.5V
Swept switching levels:	TTL 1.2V CMOS 2.5V
Swept high levels:	TTL 1.9V to 4.9V CMOS 1.9V to 4.9V

Test types

Truth table (functional):	Library based functional test
Connections (MDA):	Short circuit detection Floating input detection Open circuit detection Linked pin detection
Voltage:	Resolution 10mV Range +/-10V Logic state detection
VI:	Number of channels 64 - 256 Sweep ranges -10V to +10V (programmable) Maximum test current 1mA Multi-plot with single waveform zoom
Thermal:	Indication of pin temperature

Test libraries

Library classes:	TTL 54/74 logic, CMOS, Memory, Interface, LSI, Microprocessor, PAL/EPLD, Linear, Package, Special and user defined
Package types:	DIL, SOIC, PLCC, QFP

Accessories

Standard	Automatic out-of-circuit adapter 1 x 64 way test cable 1 x 64 way split test cable 1 x V-I probe assembly 1 x BDO cable 1 x Short locator cable 1 x Ground clip 1 x PSU lead set
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Options

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External fitting	MultiLink case (cost option) with serial or parallel connection External case (cost option) which can hold up to 4 SYSTEM 8 modules.

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